

L Number	Hits	Search Text	DB	Time stamp
1	3238837	automatic test equipment or ATE or test \equipment	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:06
2	6936	process\$3 adj core\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:06
3	2824952	internal memory	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:07
4	1351284	test routine\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:07
5	1866115	test interface\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:07
6	2769670	TAP or test access port	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:07
7	1913736	BIST or built-in self test	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:08
8	3238837	automatic test equipment or ATE or test equipment	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:08
9	4566	(process\$3 adj core\$1) and (internal memory)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:08
10	2242	((process\$3 adj core\$1) and (internal memory)) and (test routine\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:09
11	2126	(test interface\$1) and (((process\$3 adj core\$1) and (internal memory)) and (test routine\$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:09
12	2112	((test interface\$1) and (((process\$3 adj core\$1) and (internal memory)) and (test routine\$1))) and (TAP or test access port)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:09

13	1821	((test interface\$1) and (((process\$3 adj core\$1) and (internal memory)) and (test routine\$1))) and (TAP or test access port)) and (BIST or built-in self test)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:09
14	1757	((test interface\$1) and (((process\$3 adj core\$1) and (internal memory)) and (test routine\$1))) and (TAP or test access port)) and (BIST or built-in self test)) and (automatic test equipment or ATE or test equipment)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:09
15	3795876	integrated circuit	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:09
16	1434	((test interface\$1) and (((process\$3 adj core\$1) and (internal memory)) and (test routine\$1))) and (TAP or test access port)) and (BIST or built-in self test)) and (automatic test equipment or ATE or test equipment)) and (integrated circuit)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:10
17	37140	ASIC	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:10
18	467	((test interface\$1) and (((process\$3 adj core\$1) and (internal memory)) and (test routine\$1))) and (TAP or test access port)) and (BIST or built-in self test)) and (automatic test equipment or ATE or test equipment)) and (integrated circuit)) and ASIC	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:10
19	5579711	host system	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:11
20	465	((test interface\$1) and (((process\$3 adj core\$1) and (internal memory)) and (test routine\$1))) and (TAP or test access port)) and (BIST or built-in self test)) and (automatic test equipment or ATE or test equipment)) and (integrated circuit)) and ASIC and (host system)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:12
21	1025258	embedded ajd processor	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:12
22	458	((test interface\$1) and (((process\$3 adj core\$1) and (internal memory)) and (test routine\$1))) and (TAP or test access port)) and (BIST or built-in self test)) and (automatic test equipment or ATE or test equipment)) and (integrated circuit)) and ASIC and (host system)) and (embedded ajd processor)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:12
23	887933	output\$4 and (test result\$1 with external terminal)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:13
24	435	((test interface\$1) and (((process\$3 adj core\$1) and (internal memory)) and (test routine\$1))) and (TAP or test access port)) and (BIST or built-in self test)) and (automatic test equipment or ATE or test equipment)) and (integrated circuit)) and ASIC and (host system)) and (embedded ajd processor)) and (output\$4 and (test result\$1 with external terminal))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:14

25	2880779	processing core	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:14
26	435	((((((((test interface\$1) and (((process\$3 adj core\$1) and (internal memory)) and (test routine\$1))) and (TAP or test access port)) and (BIST or built-in self test)) and (automatic test equipment or ATE or test equipment)) and (integrated circuit)) and ASIC) and (host system)) and (embedded ajd processor)) and (output\$4 and (test result\$1 with external terminal))) and (processing core)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:14
27	38538	ASIC\$2	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:15
28	435	((((((((test interface\$1) and (((process\$3 adj core\$1) and (internal memory)) and (test routine\$1))) and (TAP or test access port)) and (BIST or built-in self test)) and (automatic test equipment or ATE or test equipment)) and (integrated circuit)) and ASIC) and (host system)) and (embedded ajd processor)) and (output\$4 and (test result\$1 with external terminal))) and (processing core)) and ASIC\$2	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:15
29	234490	execut\$3 adj test routine\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:15
30	266	((((((((test interface\$1) and (((process\$3 adj core\$1) and (internal memory)) and (test routine\$1))) and (TAP or test access port)) and (BIST or built-in self test)) and (automatic test equipment or ATE or test equipment)) and (integrated circuit)) and ASIC) and (host system)) and (embedded ajd processor)) and (output\$4 and (test result\$1 with external terminal))) and (processing core)) and ASIC\$2) and (execut\$3 adj test routine\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:16
31	91985	(indicat\$3 or detect\$3 or identify\$3) and ((type\$1 or location\$1) with (error\$1 or fault\$1 or failure\$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:18
32	55	((((((((test interface\$1) and (((process\$3 adj core\$1) and (internal memory)) and (test routine\$1))) and (TAP or test access port)) and (BIST or built-in self test)) and (automatic test equipment or ATE or test equipment)) and (integrated circuit)) and ASIC) and (host system)) and (embedded ajd processor)) and (output\$4 and (test result\$1 with external terminal))) and (processing core)) and ASIC\$2) and (execut\$3 adj test routine\$1)) and ((indicat\$3 or detect\$3 or identify\$3) and ((type\$1 or location\$1) with (error\$1 or fault\$1 or failure\$1)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:18
33	8243	714/?..ccls. or 716/?..ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:19

34	1	((((((((((((test interface\$1) and (((process\$3 adj core\$1) and (internal memory)) and (test routine\$1)))) and (TAP or test access port)) and (BIST or built-in self test)) and (automatic test equipment or ATE or test equipment)) and (integrated circuit)) and ASIC) and (host system)) and (embedded ajd processor)) and (output\$4 and (test result\$1 with external terminal))) and (processing core)) and ASIC\$2) and (execut\$3 adj test routine\$1)) and (((indicat\$3 or detect\$3 or identify\$3) and ((type\$1 or location\$1) with (error\$1 or fault\$1 or failure\$1)))) and (714/?..ccls. or 716/?..ccls.)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/25 18:19
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